List of Patent and Publications Cited by Applicant (Use several sheets if necessary) U.S. Department of Commerce Patent and Trademark Office			Docket No. N1280-00100(TSMC2003-841)			Serial No. Unassigned		
			Applicant Chung-Hui Chen et al.					
			Filing Date 02/23/2004			Group Unknown		
U. S. PATE	NT DOC	UMENTS						
Examiner Initial	Cite No.	Document No.	Kind Code (if known)	Name		Date	Class	Subclass
(J)	1.	6,507,087 B1		Yu		01/14/2003	257/529	
C/D	2.	6,445,606 B		Khoury	Khoury		365/96	
(A)	3.	6,436,738 B	31	Yu		08/20/2002	438/132	
Ç0	4.	6,208,549 B		Rao et al.		03/27/2001	365/96	
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	J			-				
FOREIGN		DOCUMENT	rs					
Examiner Initial	Cite No.	Country Number Kind Code Code				me of Patentee Applicant	Page, Columns, Lines wher Relevant Passages Appeal	re T
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	100 100			D D C CVD (TD)/TC				
Examiner Initial	Cite No.	- NON PATENT LITERATURE DOCUMENTS  (Include name of author in CAPITAL LETTERS, Title of the Article (when appropriate) title of the item (book, magazine, journal, symposium, catalog, etc.) date, pages, volume, issue number(s), publisher, city and/or country where published)						
40	5.	Ker, Ming-Dou et al., "CAPACITOR-COUPLE ESD PROTECTION CIRCUIT FOR DEEP-SUBMICRON LOW-VOLTAGE CMOS ASIC", IEEE Transactions on Very Large Scale Integration (VLSI) Systems, Vol. 4, No. 3, (SEPT. 1996), pp. 307-321						
Sp	6.	Ker, Ming-Dou et al., "COMPLEMENTARY-SCR ESD PROTECTION CIRCUIT WITH INTERDIGITATED FINGER-TYPE LAYOUT FOR INPUT PADS OF SUBMICRON CMOS IC'S", IEEE Transactions on Electron Devices, Vol. 42, No. 7, (JUL 1995), pp. 1297-1304						
	. ~	Wu et al., A NEW ON-CHIP ESD PROTECTION CIRCUIT WITH DUAL PARASITIC SCR STRUCTURES FOR CMOS VLSI, IEEE Journal of Solid-State Circuits, Vol. 27, No. 3, (MAR 1992), pp. 274-280						
4)	7.		92), pp. 274-280					

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

DATE CONSIDERED

**EXAMINER** 

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